

# Recitation Class 3

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# Outline

## Chapter 4-II The Semiconductor in Equilibrium

## Chapter 5-I Carrier Transport Phenomena

Drift

Diffusion

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## Chapter 5-I Carrier Transport Phenomena

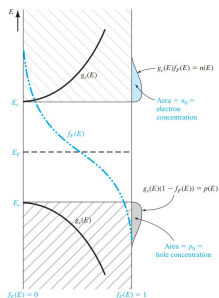
Drift

Diffusion

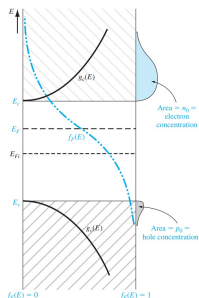
## One More Equation

$$E_{Fi} - E_{midgap} = \frac{1}{2}kT \ln \left( \frac{N_v}{N_c} \right) = \frac{3}{4}kT \ln \left( \frac{m_p^*}{m_n^*} \right)$$

# The Extrinsic Semiconductor



(a) Intrinsic



(b) n-type semiconductor

**Figure:** Density of states functions, Fermi-Dirac probability function, and areas representing electron and hole concentrations

# The Extrinsic Semiconductor

$$n_0 = N_c \exp\left(\frac{E_F - E_c}{kT}\right)$$

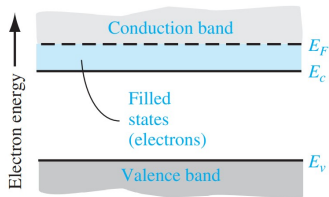
$$p_0 = N_v \exp\left(\frac{E_v - E_F}{kT}\right)$$

$$n_0 p_0 = N_c N_v \exp\left(-\frac{E_g}{kT}\right) = n_i^2$$

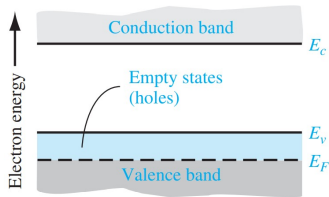
# Degenerate Semiconductors

Impurity concentration increases  $\Rightarrow$  distance between impurity atoms decreases  $\Rightarrow$  donor electrons start to interact with each other  $\Rightarrow$  single discrete donor energy level splits into a band  $\Rightarrow$  overlaps with conduction band.

# Degenerate Semiconductors



(a) n-type



(b) p-type

**Figure:** Simplified energy-band diagrams for degenerately doped semiconductors



# Statistics of Donors and Acceptors

$$f_d(E) = \frac{1}{1 + \frac{1}{2} \exp\left(\frac{E_d - E_F}{kT}\right)}$$

$$n_d = f_d(E)N_d = N_d - N_d^+$$

where  $N_d^+$  is the concentration of ionized donors.

$$f_a(E) = \frac{1}{1 + \frac{1}{g} \exp\left(\frac{E_F - E_a}{kT}\right)}$$

$1/g$  is the degeneracy factor, normally taken as 4 for acceptor level in silicon and gallium arsenide (because of detailed band structure).

$$n_a = f_a(E)N_a = N_a - N_a^+$$

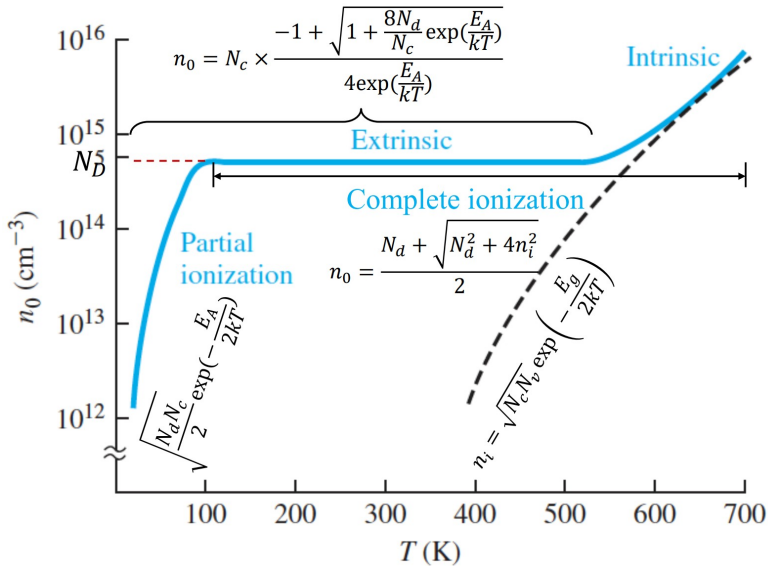
# Statistics of Donors and Acceptors

We calculate the relative number of electrons in the donor state compared with the total number of electrons: (assuming  $(E_d - E_F) \gg kT$ )

$$\frac{n_d}{n_d + n_0} = \frac{1}{1 + \frac{N_c}{2N_d} \exp \left[ \frac{-(E_c - E_d)}{kT} \right]}$$

**Example:** Determine the fraction of total electrons still in the donor states at  $T = 300K$ . Consider phosphorus doping in silicon, for  $T = 300K$ , at a concentration of  $N_d = 10^{16} cm^{-3}$ .

**Answer:** 0.41%. Very few electrons remains in the donor states (completely ionized).



# Two Important Equations

$$n_0 = \frac{N_d}{2} + \sqrt{\frac{N_d^2}{4} + n_i^2}$$

Charge neutrality:

$$n_0 = p_0 + N_d^+$$

Complete ionization:

$$n_0 = \frac{n_i^2}{n_0} + N_d$$
$$\Rightarrow n_0^2 - N_d n_0 - n_i^2 = 0$$

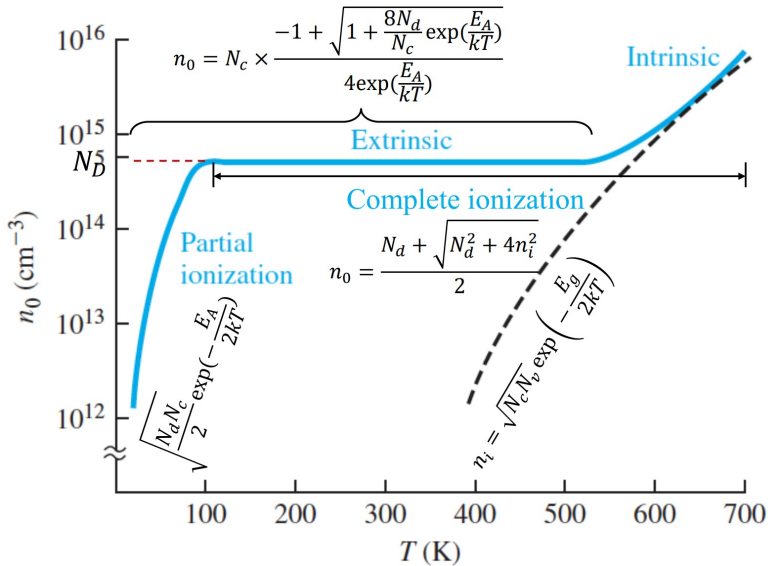
## Two Important Equations

$$n_0 = N_c \times \frac{-1 + \sqrt{1 + \frac{8N_d}{N_c} \exp\left(\frac{E_A}{kT}\right)}}{4 \exp\left(\frac{E_A}{kT}\right)}$$

$$n_0 = N_d^+ \quad \text{when } T \text{ is not high}$$

$$\begin{aligned} n_0 &= \frac{N_d}{1 + 2 \exp\left(\frac{E_F - E_d}{kT}\right)} \\ &= \frac{N_d}{1 + 2 \exp\left(\frac{E_c - E_d}{kT}\right) \exp\left(\frac{E_F - E_c}{kT}\right)} \\ &= \frac{N_d}{1 + 2 \exp\left(\frac{E_A}{kT}\right) \frac{n_0}{N_c}} \end{aligned}$$

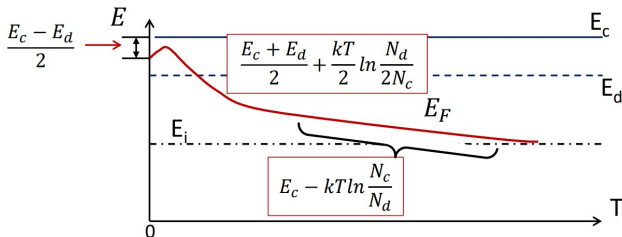
$$\Rightarrow 2 \exp\left(\frac{E_A}{kT}\right) n_0^2 + N_c n_0 - N_d N_c = 0$$



# Fermi Level Position

$$E_F = E_c + kT \ln \left( \frac{\sqrt{1 + \frac{8N_d}{N_c} \exp\left(\frac{E_A}{kT}\right)} - 1}{4 \exp\left(\frac{E_A}{kT}\right)} \right)$$

$$= \begin{cases} \frac{E_c + E_D}{2} + \frac{kT}{2} \ln \frac{N_d}{2N_c}, & T \text{ small} \\ E_c - kT \ln \frac{N_c}{N_d}, & T \text{ big} \end{cases}$$



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# Drift

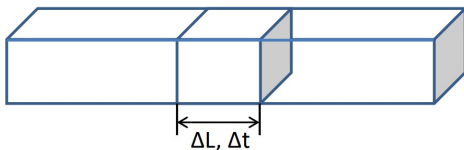


Figure: for p type semiconductor ( $p_0 \gg n_0$ )

$$I_{drf} = \frac{\Delta Q}{\Delta t} = \frac{qp_0 A_c \Delta L}{\Delta t} = qp_0 A_c v_d$$

How to derive  $v_d$ ?

$$v = \frac{qEt}{m_{cp}^*},$$

where  $\tau_{cp}$  - the mean time between collisions

$$v_d \approx \left( \frac{q\tau_{cp}}{m_{cp}^*} \right) E = \mu_p E$$

# Drift

$$J_{drf} = q(p_0\mu_p + n_0\mu_n)E$$

$$\rho = \frac{1}{\sigma} = \frac{1}{q(\mu_n n + \mu_p p)}$$

$\rho$  : resistivity

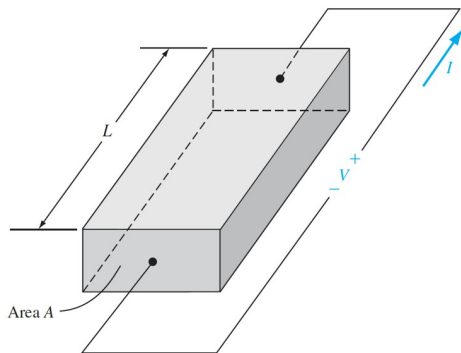
$\sigma$  : conductivity

	$\mu_n$ (cm <sup>2</sup> /V-s)	$\mu_p$ (cm <sup>2</sup> /V-s)
Silicon	1350	480
Gallium arsenide	8500	400
Germanium	3900	1900

**Figure:** Typical mobility values at  $T = 300K$  and low doping concentrations

## Example

A bar of p-type silicon at  $300K$  in the figure below has a cross-sectional area  $A = 10^{-6} \text{ cm}^2$  and a length  $L = 1.2 \times 10^{-3} \text{ cm}$ . For an applied voltage of  $5V$ , a current of  $2 \text{ mA}$  is required. What is the required (a) resistance, (b) resistivity, and (c) impurity doping concentration? (d) What is the resulting hole mobility? ( $p = 7 \times 10^{15} \text{ cm}^{-3}$ )



# Mobility Effect - Scattering

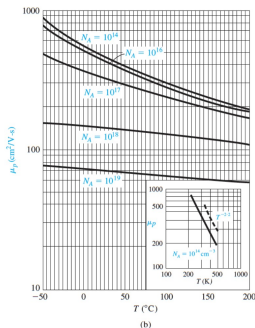
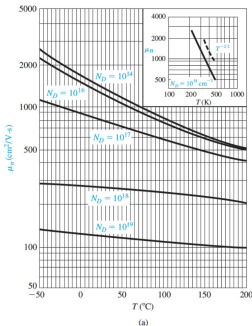
- *Lattice scattering / phonon scattering*

Lattice scatterings shorten  $\tau_{cp} \implies \mu_L \propto T^{-3/2}$

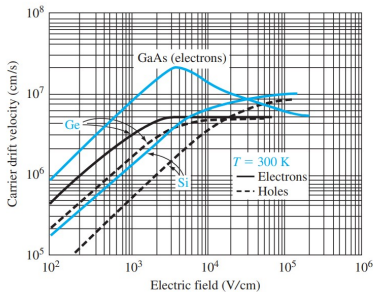
- *Ionized impurity scattering*

Impurity scatterings shorten  $\tau_{cp} \implies \mu_I \propto \frac{T^{3/2}}{N_d^+ + N_a^-}$

$$\frac{1}{\mu} = \frac{1}{\mu_L} + \frac{1}{\mu_I}$$



## Velocity Saturation

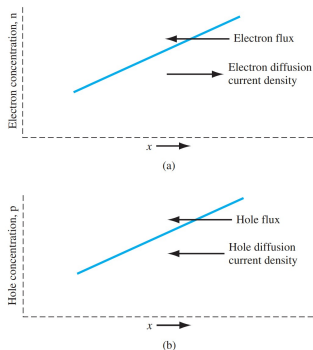


$$V_n = \frac{V_s}{\left[1 + \left(\frac{E_{on}}{E}\right)^2\right]^{1/2}}$$

$$V_p = \frac{V_s}{\left[ 1 + \left( \frac{E_{op}}{E} \right)^2 \right]^{1/2}}$$

In silicon at  $T = 300K$ ,  $v_s = 10^7 \text{ cm/s}$ ,  $E_{on} = 7 \times 10^3 \text{ V/cm}$ ,  $E_{op} = 2 \times 10^4 \text{ V/cm}$ .

# Diffusion



**Figure:** (a) Diffusion of electrons due to a density gradient. (b) Diffusion of holes due to a density gradient.

$$J_{nx|dif} = eD_n \frac{dn}{dx}$$

$$J_{px|dif} = -eD_p \frac{dp}{dx}$$

End